

Notice of References Cited	Application/Control No. 10/003,594	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Sargon N Nano	Art Unit 2157	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,493,104	12-2002	Cromer et al.	358/1.15
	B	US-6,840,441	01-2005	Monaghan et al.	235/379
	C	US-6,167,514	12-2000	Matsui et al.	713/150
	D	US-5,699,495	12-1997	Snipp, David B.	358/1.15
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
	O					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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